

Notice of References Cited	Application/Control No. 10/787,154	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Neil R. McLean	Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,402,170 A	03-1995	Parulski et al.	348/211.6
*	B	US-6,141,111 A	10-2000	Kato, Hiroyuki	358/1.15
*	C	US-2001/0048472 A1	12-2001	Inoue et al.	348/207
*	D	US-2002/0140951 A1	10-2002	Nihei, Kaname	358/1.2
*	E	US-2003/0081234 A1	05-2003	Wiley, Jeffrey G.	358/1.13
*	F	US-6,646,756 B2	11-2003	Moriyama et al.	358/1.15
*	G	US-7,224,480 B2	05-2007	Tanaka et al.	358/1.15
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.